TR5001V SII
MULTI CORE SERIES

- Multi-Core Parallel Test
- Reliable Vacuum Fixture Testing
- Non-Multiplexing 1:1 per Pin Architecture
- Scalable MDA to ICT and Functional Test
- High Accuracy and High Throughput
- Durable Quick Disconnection Interface

IN-CIRCUIT TESTER

S P E C I F I C A T I O N S

General

	TR5001V SII	TR5001DV SII	TR5001QV SII
Multi-core/Single Core Test (Cores)	1	1, 2	1, 2, 4
Maximum Analog/Hybrid Test Points	3456	3328	4096
Operating System	Microsoft® Windows compatible PC with USB, Windows 10		
Power Requirement	200 – 240 VAC, single phase, 50/60 Hz, 3 kVA		
Air Requirement	Dry air 4 – 8 kg/cm², air consumption: 20 liters/cycle		
Vacuum Requirement	min. -0.86 bar (-12.6 psi), exhaust: 25m³/h		
Fixture Type	Vacuum fixture with Quick Disconnection Interface		

Analog Hardware

Measurement Switching Matrix	6-wire measurement
Programmable Frequency	100 Hz, 1 kHz, 10 kHz, 100 kHz
Programmable DC Voltage Source	±10V max, resolution: 10 mV
Programmable DC Current Source	+100 mA max, resolution: 0.2 mA
Programmable AC Voltage Source	10 Vpp max, resolution: 10 mV
Programmable High Voltage Current Source	53 V / 100 mA max

Component Measurement Capability	
Resistance	30 mohm – 40 Mohm
Capacitance	5 pF – 40 mF
Inductance	5 µH – 60 H

| Analog Measurement	
AC Voltmeter	0 – 100 Vp
DC Voltmeter	0 – ±100 V; resolution: 2.5 mV – 50 mV
DC Ammeter	1 µA – 100 mA; resolution: 30 nA – 30 µA

Optional Hardware

Analog Test	
TestJet Technology	Vectorless open circuit detection
Arbitrary Waveform Generator (AWG)	Frequency range 0 – 100 kHz; resolution: 0.15 Hz, BW: 100kHz max

Digital Test	
Non-multiplexing 1:1 per pin architecture with independent per-pin level setting	
Pin Drivers	Programmable levels 0.5 V to 4 V
Pin Receivers	Programmable levels 0 V to 5 V
Pull-up/Pull-down Resistor	4.7 K
DUT Power Supplies	5 V@3 A, 3.3 V@3 A, 12 V@3A, -12 V@1 A and 24 V@3 A 2 Channel programmable power 0.2 V – 3 V@2 A or 3 V – 24 V@3 A
APPS Programmable DUT Power Supply	75 V / 8 A max, 200 W maximum output power
On-board Programming of Flash & EEPROM Memories	
MAC Address Programming	Supports MAC address programming with server supplied MAC address
Boundary Scan	Includes BScan Chain Test, BScan Cluster Test, BScan Virtual Nails Test, BScan Virtual Chain Test and IEEE1149.6 Test
ToggleScan Test	Advanced test technology that combines with BScan and Vectorless test functions to detect pin open or short issues
Tree Test Facilities with BGA Test	Pattern generator for detection of pin opens for BGA/VLSI chips

Dimensions/Weight

1480 (58.3)
1080 (42.5)
1270 (50.0)
900 (35.4)
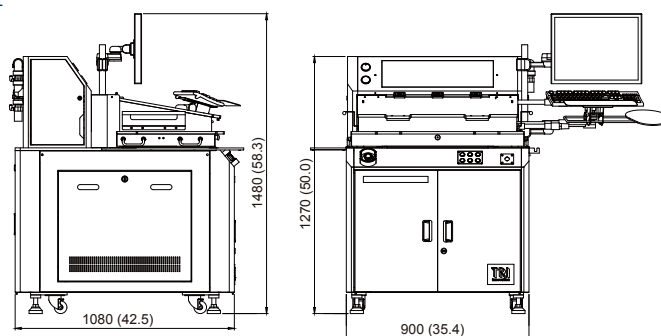
Unit : mm (in.)

	TR5001V SII	TR5001DV SII	TR5001QV SII
Weight	350 (772 lbs)		370 kg (816 lbs)